1. General description

High voltage, high speed, planar passivated NPN power switching transistor with integrated anti-parallel E-C diode in a SOT186A (TO220F) "full pack" plastic package.

2. Features and benefits

- Fast switching
- High voltage capability
- · Integrated anti-parallel E-C diode
- Isolated package
- · Very low switching and conduction losses

3. Applications

- DC-to-DC converters
- · Electronic lighting ballasts
- Inverters
- · Motor control systems

4. Pinning information

Table 1. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	В	base	mb	C -
2	С	collector		
3	E	emitter		В
mb	n.c.	mounting base; isolated	1 2 3 TO-220F (SOT186A)	 E sym131

NPN power transistor with integrated diode

5. Ordering information

Table 2. Ordering information

Type number	Package					
	Name	Description	Version			
BUJD203AX	TO-220F	plastic single-ended package; isolated heatsink mounted; 1 mounting hole; 3-lead TO-220 "full pack"	SOT186A			

NPN power transistor with integrated diode

6. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CESM}	collector-emitter peak voltage	V _{BE} = 0 V	-	850	V
V_{CBO}	collector-base voltage	I _E = 0 A	-	850	V
V _{CEO}	collector-emitter voltage	I _B = 0 A	-	425	V
I _C	collector current	DC; Fig. 1; Fig. 2; Fig. 3	-	4	Α
I _{CM}	peak collector current	Fig. 1; Fig. 2; Fig. 3	-	8	Α
I _B	base current	DC	-	2	Α
I _{BM}	peak base current		-	4	Α
P _{tot}	total power dissipation	T _h ≤ 25 °C; <u>Fig. 4</u>	-	26	W
T _{stg}	storage temperature		-65	150	°C
T _j	junction temperature		-	150	°C

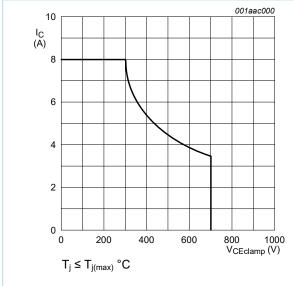
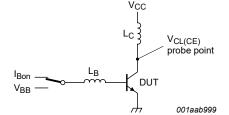


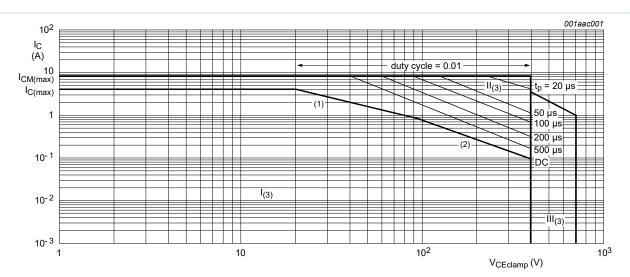
Fig. 1. Reverse bias safe operating area



$$\begin{split} &V_{CL(CE)} \leq 1000 \; V; \, V_{CC} = 150 \; V; \, V_{BB} = \text{--} 5 \; V; \\ &L_{B} = 1 \; \mu H; \, L_{C} = 200 \; \mu H \end{split}$$

Fig. 2. Test circuit for reverse bias safe operating area

NPN power transistor with integrated diode



- 1) Ptot maximum and Ptot peak maximum lines
- 2) Second breakdown limits
- 3) I = Region of permissable DC operation
 - II = Extension for repetitive pulse operation
 - III = Extension during turn-on in single transistor converters provided that $R_{BE} \le 100~\Omega$ and $tp \le 0.6~\mu s$

Fig. 3. Forward bias safe operating area for Tmb ≤ 25 °C

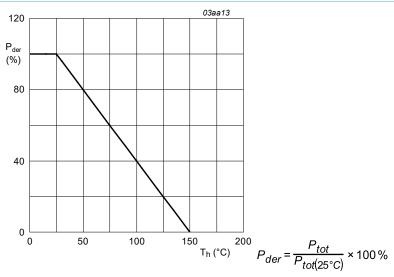


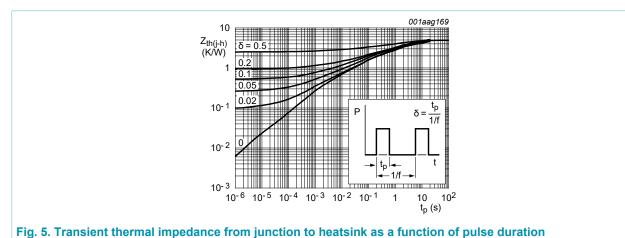
Fig. 4. Normalized total power dissipation as a function of heatsink temperature

NPN power transistor with integrated diode

7. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-h)}	thermal resistance from junction to heatsink	with heatsink compound; Fig. 5	-	-	4.8	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	in free air	-	55	-	K/W



8. Isolation characteristics

Table 5. Isolation characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	50 Hz \leq f \leq 60 Hz; RH \leq 65 %; T _h = 25 °C; from all terminals to external heatsink; clean and dust free	-	-	2500	V
C _{isol}	isolation capacitance	T _h = 25 °C; f = 1 MHz; from collector to external heatsink	-	10	-	pF

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NPN power transistor with integrated diode

9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions		Min	Тур	Max	Uni
Static chara	acteristics						
I _{CES}	collector-emitter cut-off	V _{BE} = 0 V; V _{CE} = 850 V; T _j = 125 °C	[1]	-	-	2	mA
	current (base shorted)	V _{BE} = 0 V; V _{CE} = 850 V; T _j = 25 °C	[1]	-	-	1	mA
I _{CBO}	collector-base cut-off current (emitter open)	$V_{CB} = 850 \text{ V}; I_{E} = 0 \text{ A}$	[1]	-	-	1	mA
СЕО	collector-emitter cut-off current (base open)	$V_{CE} = 425 \text{ V}; I_{B} = 0 \text{ A}$	[1]	-	-	0.1	mA
ЕВО	emitter-base cut-off current (collector open)	$V_{EB} = 7 \text{ V}; I_{C} = 0 \text{ A}$		-	-	10	mA
V_{CEOsus}	collector-emitter sustaining voltage (base open)	I _B = 0 A; I _C = 10 mA; L _C = 25 mH; Fig. 6; Fig. 7		400	450	-	V
V _{CEsat}	collector-emitter saturation voltage	I _C = 3 A; I _B = 0.6 A; <u>Fig. 8</u> ; <u>Fig. 9</u>		-	0.29	1	V
V_{BEsat}	base-emitter saturation voltage	$I_C = 3 \text{ A}; I_B = 0.6 \text{ A}; Fig. 10$		-	0.99	1.5	V
V _F	forward voltage	I _F = 2 A; T _j = 25 °C		-	1.04	1.5	V
h _{FE}	DC current gain	$I_C = 1 \text{ mA}$; $V_{CE} = 5 \text{ V}$; $T_h = 25 \text{ °C}$; Fig. 11		10	15	32	
		I_C = 500 mA; V_{CE} = 5 V; T_h = 25 °C; Fig. 11		13	21	32	
		I _C = 2 A; V _{CE} = 5 V; T _h = 25 °C; <u>Fig. 11</u>		11	16	22	
		I _C = 3 A; V _{CE} = 5 V; T _h = 25 °C; <u>Fig. 11</u>		-	12.5	-	
Dynamic ch	naracteristics						
t _{on}	turn-on time	I _C = 2.5 A; I _{Bon} = 0.5 A; I _{Boff} = -0.5 A;		-	0.52	0.6	μs
t _s	storage time	R_L = 75 Ω; T_j = 25 °C; resistive load; Fig. 12; Fig. 13		-	2.7	3.3	μs
		I_C = 2 A; I_{Bon} = 0.4 A; V_{BB} = -5 V; L_B = 1 μ H; T_j = 25 °C; inductive load; <u>Fig. 14</u> ; <u>Fig. 15</u>		-	1.2	1.4	μs
		I_C = 2 A; I_{Bon} = 0.4 A; V_{BB} = -5 V; L_B = 1 μ H; T_j = 100 °C; inductive load; Fig. 14; Fig. 15		-	-	1.8	μs
t _f	fall time	I_C = 2.5 A; I_{Bon} = 0.5 A; I_{Boff} = -0.5 A; R_L = 75 Ω ; resistive load; Fig. 12; Fig. 13		-	0.3	0.35	μs
		I _C = 2 A; I _{Bon} = 0.4 A; V _{BB} = -5 V;		-	-	0.12	μs
		L _B = 1 μH; inductive load; <u>Fig. 14;</u> <u>Fig. 15</u>		-	0.03	0.06	μs
							_

[1] Measured with half-sine wave voltage (curve tracer)

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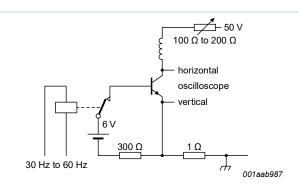


Fig. 6. Test circuit for collector-emitter sustaining voltage

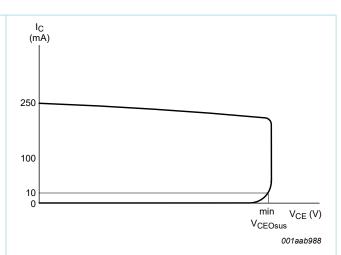


Fig. 7. Oscilloscope display for collector-emitter sustaining voltage test waveform

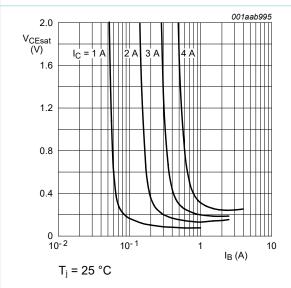


Fig. 8. Collector-emitter saturation voltage as a function of base current; typical values

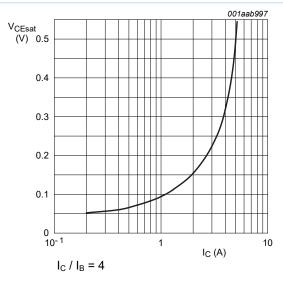


Fig. 9. Collector-emitter saturation voltage as a function of collector current; typical values

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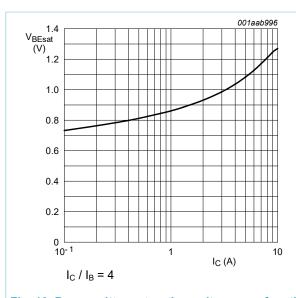


Fig. 10. Base-emitter saturation voltage as a function of collector current; typical values

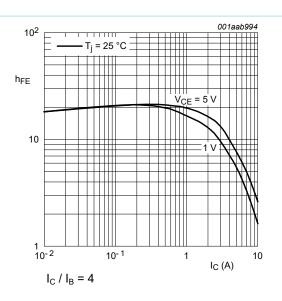
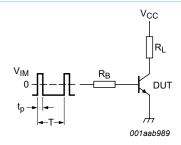


Fig. 11. DC current gain as a function of collector current; typical values



 V_{IM} = - 6 to + 8 V; V_{CC} = 250 V; t_p = 20 us; δ = t_p /T = 0.01 R_B and R_L calculated from I_{Con} and I_{Bon} requirements.

Fig. 12. Test circuit for resistive load switching

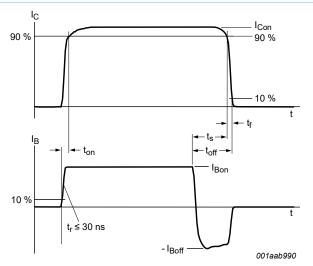
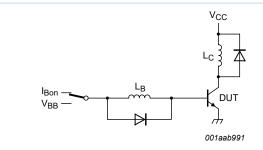


Fig. 13. Switching times waveforms for resistive load

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 V_{CC} = 300 V; V_{BB} = - 5 V; L_{C} = 200 $\mu H;$ L_{B} = 1 μH

Fig. 14. Test circuit for inductive load switching

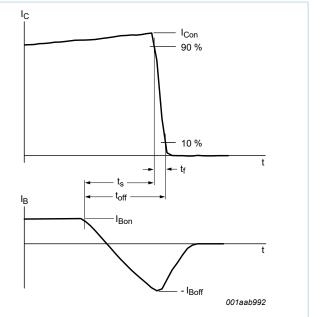
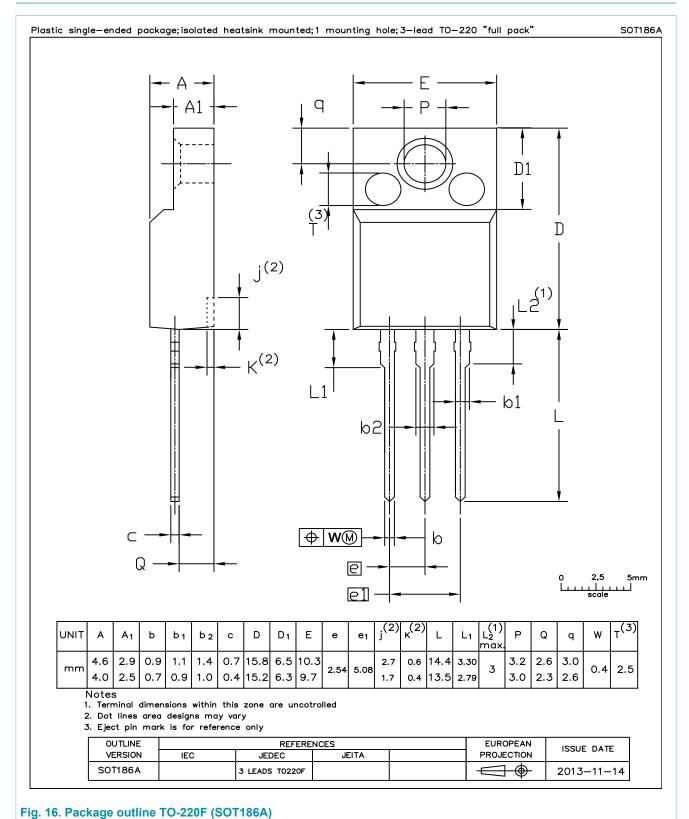


Fig. 15. Switching times waveforms for inductive load

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10. Package outline



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11. Legal information

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Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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BUJD203AX

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